

Call for Papers

Call for Papers for a Special Issue of IEEE Transactions on Device and Material Reliability on “Nonvolatile Memory Reliability”

This special issue will document the progress in the area of nonvolatile memories, exploring recent achievement in the field and future progress. Research in nonvolatile memories seeks to exploit material properties to realize devices even more resembling the “ideal nonvolatile memory”: unlimited retention in every environment, unlimited program/erase/read cycles.

In this scenario, the field of nonvolatile memories has grown significantly, and a wide range of non-volatile memory based on different operation principles have been proposed in the years: they range from memories based on the classical Floating Gate concept (EPROM, EEPROM, Flash) and on charge trapping (SONOS; NROM, Nanocrystal), to nonvolatile memories exploiting the properties of new material (Ferroelectric, Magnetoelectric, Phase Change Devices).

This issue will contain invited and contributed papers covering a range of topics in nonvolatile memory reliability. The topics of interest include, but are not limited to:

Flash Memories based on Floating Gate: EPROM, EEPROM, Flash, ...
Flash Memories based on Charge Trapping: NROM, Nanocrystal, ...
Non-Volatile Memories based on New Technologies: Phase Change Memories,
Ferroelectric Memories, Magnetoelectric Memories

Submission deadline: June 30, 2004

Please submit papers by using the website: <http://tdmr-ieee.manuscriptcentral.com>. For any questions or help needed to upload your paper, contact:

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